Issue Classification



App	licat	ion/C	ontrol	No
-----	-------	-------	--------	----

09446425

CAPELLARO ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Pich, Ponnoreay

Art Unit

2135

ORIGINAL				INTERNATIONAL CLASSIFICATION											
CLASS S			SUBCLASS	BCLASS CLAIMED						- 1	ION-CL	AIMED			
713			152			Н	0	4	L	9 / 00 (2006	_	$oxed{\Box}$			
CROSS REFERENCE(S)				G	0	6	F	15 / 16 (2006		-	ļ				
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)					OCK)	н	0	4	К	1 / 00 (2006.01.	01)	-			
713	150	151	NE SUBCLA								-	+-	ļ .		
709	229	230		 		+						-			
380	255					1						+	<u> </u>		
													ļ		
						 							ļ		
				ļ		-									
				 		+					+	-	<u> </u>		
				 								-			
									_			-			
				1	·	\vdash						+		 	
						1					+		<u> </u>		
				-								 			
						1						1			•
												1			-
												- 		<u> </u>	
													 		
						<u> </u>							ļ		
												<u> </u>	<u> </u>		
						<u> </u>						_			
			<u>.</u>	ļ								-			
						├-					_				
						┢						-			· · · · · · · · · · · · · · · · · · ·
					<u> </u>	\vdash					+			\vdash	
				1		\vdash	-	-	-			+		\vdash	
				1	1	1			_		-	+			
		1			1//	 				A	\dashv		-		
Pich, Ponnoreay 8/31/07 (Assistant Examiner) (Date)			1 lu							Total Claims Allowed:					
(Legal Instruments Examiner)				1	SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100 (Primary Examiner) (Date)								n(s)	O.G. Print Figur	